

Attorney Docket No. 04083/LH

**IN THE UNITED STATES PATENT
AND TRADEMARK OFFICE**

Applicant(s): Takashi YONEYAMA, et al.

Serial No. : 10/773,524

Confirm. No.: 7190

Filed : February 6, 2004

For : DEFECT INSPECTION APPARATUS AND
DEFECT INSPECTION METHOD

Art Unit : 2624

Examiner : Tsung Yin Tsai

AMENDMENT FILED WITH RCE

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

S I R :

This is Amendment is being filed along with a Request for Continued Examination (RCE) in response to the Final Office Action mailed November 26, 2007, the term for response to which is extended by 2 months by Petition filed concurrently herewith to expire on April 26, 2008 (Saturday), which is automatically extended to Monday, April 28, 2008.

Amendments to the Claims are set forth in the listing of claims which begins on page 2 of this paper. Claims 1, 5-8 and 13-17 are canceled; claims 9 and 18 are amended; and claims 2-4, 10-12, and 19-26 are maintained.

Remarks begin on page 11 of this paper.

This paper is being submitted
via EFS-Web on April 28, 2008

In the event that this Paper is
late filed, and the necessary
petition for extension of time
is not filed concurrently
herewith, please consider this
as a Petition for the requisite
extension of time, and to the
extent not already paid,
authorization to charge the
extension fee to Account
No. 06-1378. In addition,
authorization is hereby given to
charge any fees for which
payment has not been submitted,
or to credit any overpayments,
to Account No. 06-1378.